

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/767,614	OGAWA, HIDEHIKO	
		Examiner	Art Unit	Page 1 of 1
		Thomas D. Lee	2624	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,798,845	08-1998	Baek et al.	358/434
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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